

UNIVERSITY OF CALIFORNIA
College of Engineering
Department of Electrical Engineering and Computer Sciences

EECS 130
Spring 2006

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HOMEWORK SET NO. 2
Due: Thursday, 2nd February, 2006

1. (a) Semiconductor is doped with an impurity concentration N such that $N \gg n_i$ and all the impurities are ionized. Also, $n = N$ and $p = n_i^2/N$. Is the impurity a donor or an acceptor? Explain.
(b) In a germanium sample maintained under equilibrium conditions near room temperature, it is known that $n_i = 10^{13} \text{ cm}^{-3}$, $n = 2p$, and $N_A = 0$. Determine n and N_D .
2. (a) The electron concentration in a piece of Si maintained at 300 K under equilibrium condition is 10^5 cm^{-3} . What is the hole concentration?
(b) For a silicon sample maintained at $T = 300 \text{ K}$, the Fermi level is located 0.301 eV above the E_v . What are the hole and electron concentrations?
3. A sample of silicon is doped with $N_d = 10^{16} \text{ cm}^{-3}$ and $N_a = 10^{15} \text{ cm}^{-3}$.
(a) Find n_0 and p_0 assuming complete ionization of the dopants.
(b) Locate E_f .
(c) Sketch the energy band diagram. Identify E_c , E_v , E_f and E_i on your drawing. Indicate the band gap.
4. An electron is moving in a piece of lightly doped silicon under an applied field at 300K so that its drift velocity is one-tenth of its thermal velocity. What is the applied electric field? Calculate the average number of collisions it will experience in traversing by drift a region 1 μm long.
5. A sample of N-type silicon is at room temperature. When an electric field with strength of 1000V/cm is applied to the sample, the hole velocity is measured and found to be $2 \times 10^5 \text{ cm/sec}$.
(a) Estimate the equilibrium electron and hole densities, indicating which the minority carrier is.
(b) Find the position of E_f with respect to E_c and E_v .
(c) The sample is used to make an integrated circuit resistor. The width and height of the sample are 10 μm and 1.5 μm , respectively, and the length of the sample is 20 μm . Calculate the resistance of the sample.